

AD-A142 435

PROTON-INDUCED SINGLE EVENT UPSETS IN 71
EARTH-SATELLITE ENVIRONMENTS(U) NAVAL RESEARCH LAB
WASHINGTON DC W L BENDEL 14 JUN 84 NRL-MR-5384

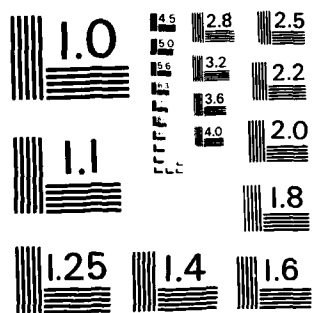
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SECURITY CLASSIFICATION OF THIS PAGE

AD-A142435

REPORT DOCUMENTATION PAGE				
1a REPORT SECURITY CLASSIFICATION UNCLASSIFIED			1b RESTRICTIVE MARKINGS	
2a SECURITY CLASSIFICATION AUTHORITY			3 DISTRIBUTION AVAILABILITY OF REPORT	
2b DECLASSIFICATION/DOWNGRADING SCHEDULE			Approved for public release; distribution unlimited.	
4 PERFORMING ORGANIZATION REPORT NUMBER(S) NRL Memorandum Report 5364			5 MONITORING ORGANIZATION REPORT NUMBER(S)	
6a NAME OF PERFORMING ORGANIZATION Naval Research Laboratory		6b OFFICE SYMBOL (If applicable) Code 6611		7a NAME OF MONITORING ORGANIZATION
6c ADDRESS (City, State and ZIP Code) Washington, DC 20375			7b ADDRESS (City, State and ZIP Code)	
8a NAME OF FUNDING/SPONSORING ORGANIZATION DNA and NAVELEX		8b OFFICE SYMBOL (If applicable)		9 PROCUREMENT INSTRUMENT IDENTIFICATION NUMBER
8c ADDRESS (City, State and ZIP Code) Washington, DC 20305 Washington, DC 20360			10 SOURCE OF FUNDING NOS	
			PROGRAM ELEMENT NO	PROJECT NO
			TASK NO	WORK UNIT NO
11 TITLE (Include Security Classification) (See page ii)			DN080-229	
12 PERSONAL AUTHOR(S) Bendel, W.L.				
13a TYPE OF REPORT Final		13b TIME COVERED FROM TO		14 DATE OF REPORT (Yr., Mo., Day) June 14, 1984
15 PAGE COUNT 42				
16 SUPPLEMENTARY NOTATION (See page ii)				
17 COSATI CODES			18 SUBJECT TERMS (Continue on reverse if necessary and identify by block number)	
FIELD	GROUP	SUB GR	Single event upsets	
19 ABSTRACT (Continue on reverse if necessary and identify by block number) → Predicted upset rates are presented, as a function of one experimental parameter, for devices in small earth satellites. Contour maps of SEU rate versus circular orbit inclination and altitude allow predictions at 180-1400 km and 27° to 90°. A computer program is listed, permitting the reader to calculate upsets in any proton flux. deg				
20 DISTRIBUTION AVAILABILITY OF ABSTRACT UNCLASSIFIED UNLIMITED ☒ SAME AS RPT ☐ DTIC USERS ☐			21 ABSTRACT SECURITY CLASSIFICATION UNCLASSIFIED	
22a NAME OF RESPONSIBLE INDIVIDUAL W. L. Bendel			22b TELEPHONE NUMBER (Include Area Code) (202) 767-3938	22c OFFICE SYMBOL Code 6611

DD FORM 1473, 83 APR

EDITION OF 1 JAN 73 IS OBSOLETE

SECURITY CLASSIFICATION OF THIS PAGE

11. TITLE (Include Security Classification)

Proton-Induced Single Event Upsets in 71 Earth-Satellite Environments

16. SUPPLEMENTARY NOTATION

This work was partially sponsored by the Defense Nuclear Agency under Subtask X99QMXVA, work unit 00018, work unit title "Single Event Program" and by the Naval Electronic Systems Command under the NRL Spacecraft Survivability/Vulnerability Program.

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CONTENTS

Introduction.....	1
Experimental SEU Data.....	2
Nuclear Data and Theory.....	2
Semi-Empirical Equation.....	4
Complex Devices.....	6
Proton Flux Inside Spacecraft.....	6
Upset Rates.....	8
Upset Rate versus A.....	11
SEU Rate Plots.....	12
Interpolation in Circular Orbits.....	14
SEU Contour Maps.....	19
Summary.....	19
Acknowledgments.....	22
References.....	23
Appendix: Computer Program.....	25
Program Listing.....	26
Input and Output.....	28

Tables

1. SEU rates in 30 solar minimum orbits.....	9
2. SEU rates in 30 solar maximum orbits.....	10
3. SEU rates in 11 orbits.....	11

Figures

1. Experimental SEU cross sections.....	3
2. SEU equation, cross section vs. A.....	5
3. Normalized upset cross sections.....	7
4. SEU rates in 60° orbits, solar maximum.....	13
5. SEU rates vs. altitude, solar minimum.....	15
6. SEU rates vs. altitude, solar maximum.....	16
7. SEU rates vs. orbit inclination.....	17
8. Graph for SEU interpolation.....	18
9. SEU contour map, solar minimum.....	20
10. SEU contour map, solar maximum.....	21

Proton-Induced Single Event Upsets in 71 Earth-Satellite Environments

Introduction

An important consideration in the miniaturization of electronic components is the phenomenon of single event upset (SEU). This phenomenon is caused by high-energy radiation, and both internal and external sources of radiation have been implicated. These upsets are a current problem in spacecraft random access memories (RAMs). SEUs will become increasingly important because of the trend to smaller components and more complex circuitry, with more bits of memory. The upsets caused by protons will be particularly significant as satellites carrying multi-megabit memories try to operate in the earth's radiation belts.

We have reported¹ a method of predicting proton-induced SEUs in spacecraft RAMs, using an equation based on laboratory experiments. Data on a given device define the single parameter of the equation, which may be considered as a *figure of merit* for the device.² In the present report, the treatment of the method is somewhat shortened, but SEU tables are presented for many more orbital environments, within a specified shield. In addition, contour maps and information are presented to permit upset rate predictions in other circular orbits.

If a silicon chip contains any alpha-emitting impurity, a source of SEUs exists. (Surfaces of adjacent materials can also be a source of alphas.) When, for example, radium 226 decays, it emits an alpha particle with 4.78 MeV (million electron volts) of kinetic energy, and the residual nucleus recoils with 0.09 MeV. These particles produce ionization in whatever material they traverse, freeing one electron per 3.6 eV in the case of silicon. This produces 1.35 million electron-hole pairs, or about 0.22 picocoulomb. If this is sufficient to cause an error in a device (for example, change a bit in a computer memory), an SEU occurs.

Single event upsets may be countered by eliminating the sources or by hardening the circuit. Once internally-produced SEUs were recognized, specific ultrapurification procedures aimed at the heavy elements could be introduced. One can often shield against external radiation. In the case of spacecraft circuitry, which is subject to far more intense radiation than earth-bound circuits, massive shielding is out of the question; spacecraft electronics must be insensitive to SEUs. Radiation hardness is pursued by careful design, selection, and testing of all parts. In addition, error-correction capabilities are provided.

SEUs due to protons are a significant problem in electronic circuitry of earth-orbiting spacecraft. Unlike a heavier ion, mere passage of a proton does not produce sufficient ionization to upset the usual circuits at the present stage of miniaturization. However, a nuclear reaction initiated by a proton can produce sufficient ionization for an upset. The probability of such upsets can be investigated both experimentally and theoretically. These studies can be used to predict upset rates.

Several groups³⁻⁵ have investigated soft errors in RAMs using accelerator protons. The probability of upset increases rapidly as proton kinetic energy increases from about 20 to 100 MeV, then increases more slowly at higher energies. It appears that cross sections monotonically increase with energy. The results are orders-of-magnitude different for unlike RAMs.

The experimental SEU data, supplemented by nuclear theory and data, are used to develop an equation for upset cross section vs. proton energy, E . The equation uses a sensitivity parameter

A = apparent threshold.

This equation is then employed with the proton spectra inside spacecraft to calculate SEU rates as a function of orbit and the single experiment-based parameter for the device considered.

Experimental SEU Data

Data on proton-induced SEUs are presented in Fig. 1. The data on National Semiconductors MM5280, Intel C2107B, and Texas Instruments 4044 devices are taken from Refs. 4 and 6. Note that single devices of the same type may differ widely in SEU tests. The protons were obtained as a 158-MeV beam from the Harvard Cyclotron, degraded by passing through matter. Thus, the protons used in the low-energy bombardments were not monoenergetic.

The Motorola MCM 4116AC-20 and Mostek MK 4116J-2 data^{3,5} were obtained with the NRL Cyclotron and the Brookhaven Alternating Gradient Synchrotron.

The others, Signetics 8X350 and four Fairchild devices, were tested by the Jet Propulsion Laboratory group^{7,8} at a number of radiation facilities. A factor in the scatter of these data is use of different units with the same type number.

Note that SEUs are a function of the experimental set-up as well as the device. One expects results to depend upon operating voltage and orientation relative to the beam. These dependences are observed in the case of heavy ion bombardment.²

Nuclear Data and Theory

As shown elsewhere^{7,10}, the dominant upset mechanism is a function of device sensitivity and proton energy. Some devices can be upset by the ionization in a proton track and are grossly

EXPERIMENTAL S.E.U. CROSS SECTIONS

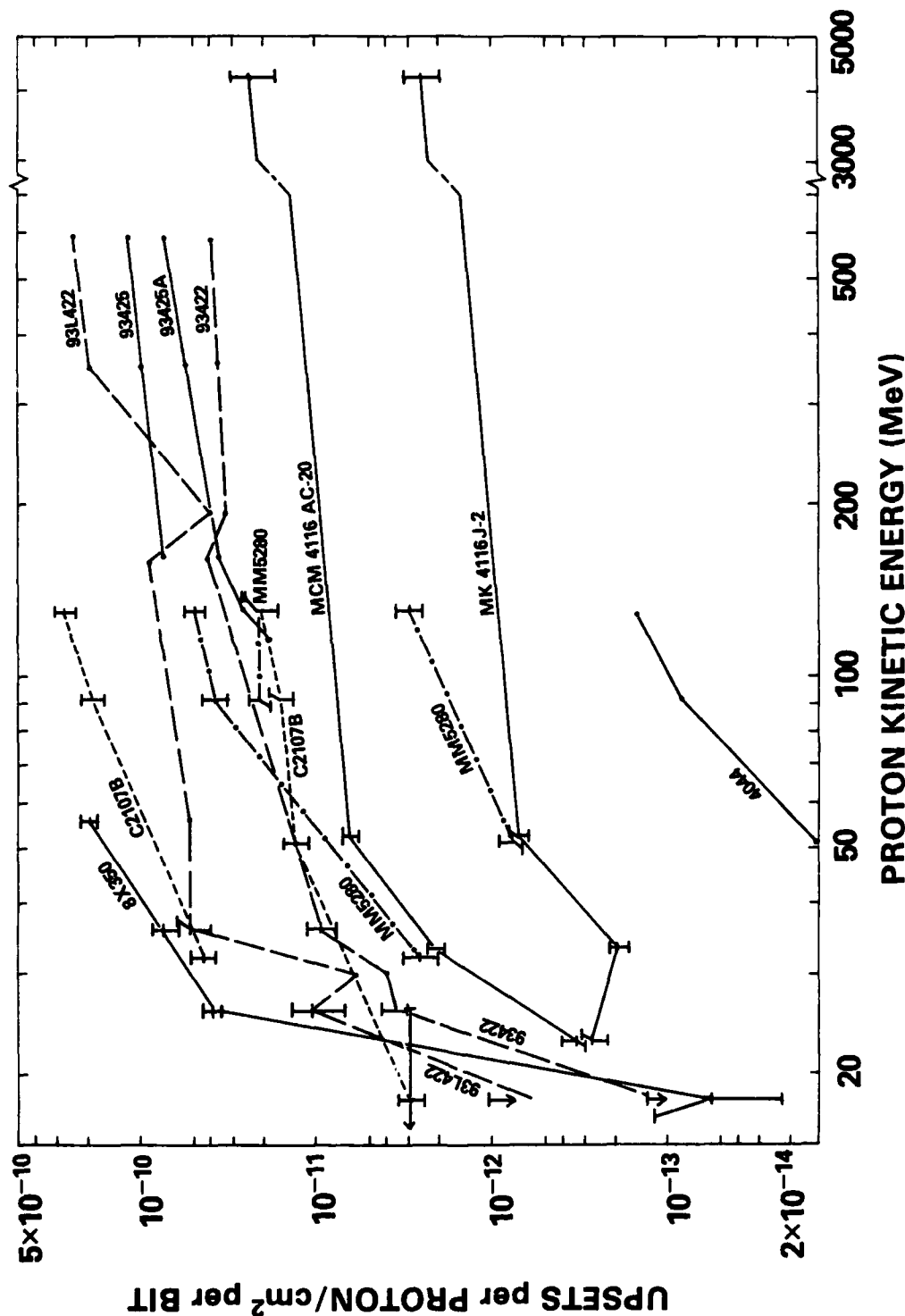


Fig. 1. Experimental upset data with protons of 18 to 4200 MeV.

unfit for spacecraft use. Hence, we should consider only devices unaffected by direct ionization in even the longest track with the funneling effect. A nuclear reaction producing a highly-ionizing track is therefore required for a proton-induced SEU. If a device upsets due to direct ionization, these SEUs are not included here. At the other extreme, proton beams have failed to upset some insensitive devices that are upset by heavy ions.

Nuclear reactions leading to upsets are discussed in Ref. 1. For SEUs due to elastic scattering, the threshold is determined by kinematics. For SEUs due to alpha-producing reactions, the apparent threshold is primarily determined by Coulomb barrier penetration cross sections, not by energy deposition. The shape of the upset cross section, being the sum over these and other reactions, is difficult to estimate, but a cross section that is proportional to $(E - A)^{1.5}$ is reasonable near threshold.¹

Total proton inelastic cross sections are reviewed by Letaw and coworkers.¹¹ In the equation which they fit to the data, the cross section approaches a constant value at high energy, being 0.4% less at 1000 MeV than at infinite energy. If the ratio of upset-producing cross section to total inelastic cross section is independent of the energy - a reasonable relationship at high energy - the SEU yield also will be essentially constant at high energy. This is consistent with the SEU data.

Semi-Empirical Equation

Experimental data on SEUs will not show the "true" threshold but will indicate an energy at which the cross section becomes immeasurably small. Therefore, our equation uses a sensitivity parameter, A , called the *apparent threshold*.

The experimental upset cross sections are fitted to a form which is constant at high proton energy, decreasing below about 1000 MeV. The data above 90 MeV are amenable to an exponential dependence upon energy. The lower energy data, as well, fit the form

$$X = X_0 [1 - \exp(-hY^m)]^n, \quad (1)$$

where X_0 is the limiting cross section. Here, h is a constant and Y is a linear function of energy which, by definition, goes to zero at $E = A$.

The function Y may be obtained from $(E - A)$ or $(E/A - 1)$. Each choice has some merit; we employ the normalized compromise relationship

$$Y = (18/A)^{0.5} (E - A), \quad (2)$$

with E and A in MeV, here and in Eq. (3). The equation adopted is

$$X = (24/A)^{1.4} [1 - \exp(-0.18 Y^{0.5})]^{1.4} \quad (3)$$

in units of 10^{-12} upsets per proton/cm² per bit. This equation is plotted in Fig. 2 for various values of A . It fits the data

SEMI-EMPIRICAL S.E.U. EQUATION

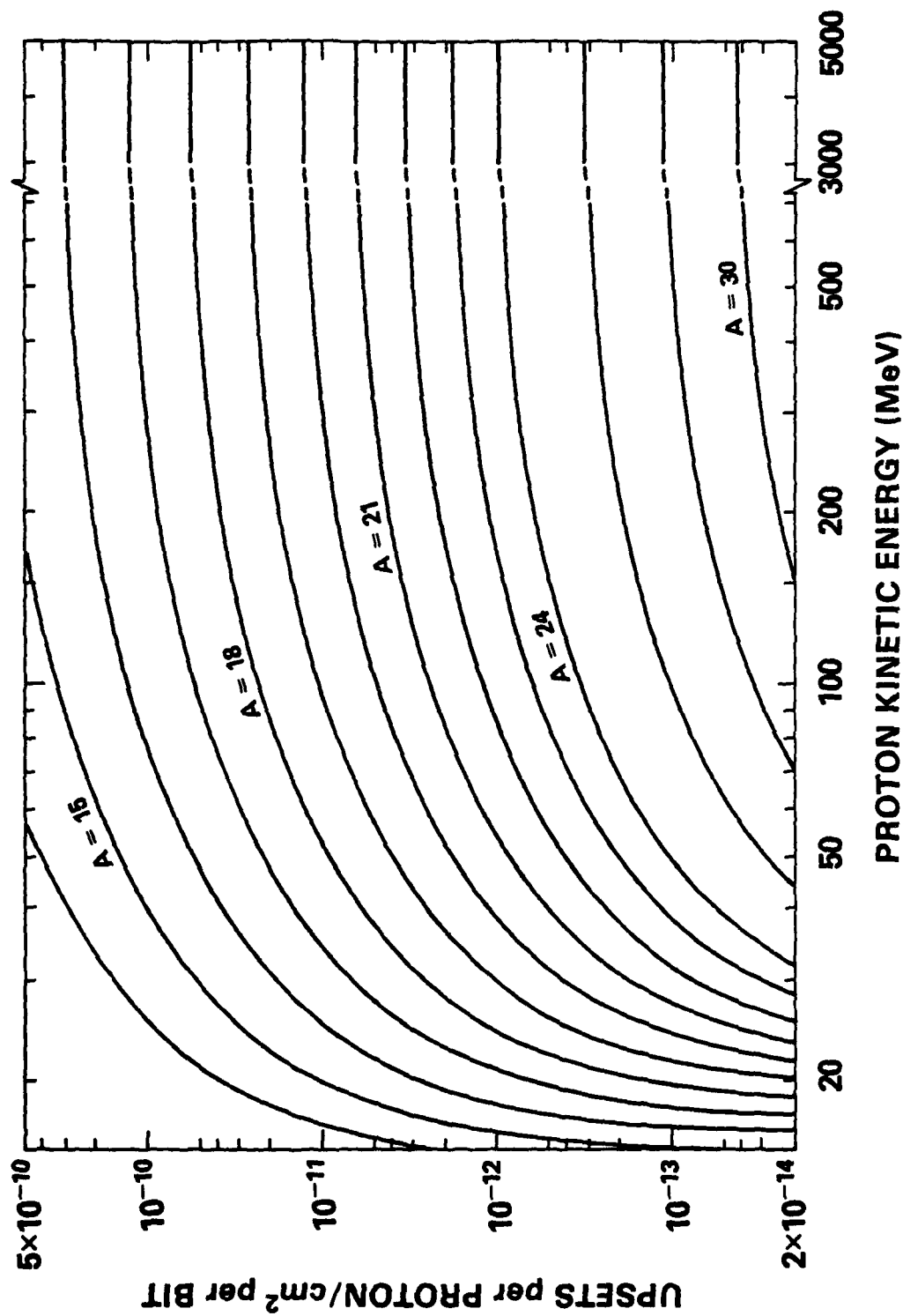


Fig. 2. Upset cross sections using Eq. (3).

quite adequately, although a larger value of mn fits a little better. The value of X is proportional to $(E - A)^2$ at $E = A$, but the average power is 1.5 between, for example, $Y = 5$ and 17.

If more consistent SEU data were available, a better empirical relationship could be developed. Data near threshold are particularly needed. It does not appear to be feasible, either scientifically or in cost effectiveness, to experimentally determine the fine structure. For a given device, one expects the SEU rate due to one reaction to rise rapidly (on a logarithmic scale) and then flatten. New rises would occur when new reactions or different parts of the circuit begin to produce a significant number of upsets.

We have determined a value of A for each device used here. Some data were given lesser weight and measurements within 4 MeV of A were ignored. The ratios of measured SEU cross sections to $X(E, A)$ are shown in Fig. 3. Note that a different value of the apparent threshold is calculated for each of the MM5280 and C2107 devices.

Petersen, Langworthy, and Diehl² propose two SEU figures of merit, one for upsets due to cosmic rays and another for upsets due to protons. They adopt the method of Ref. 1 and this report, with parameter A as the *proton SEU figure of merit*.

Complex Devices

The method given here can be applied for complex circuits as well as for memories. The device SEU cross section is measured using a test program similar to the actual programs. The cross section per bit is taken to be the measured cross section divided by the estimated number of registers involved. The value of A is then calculated with Eq. (3). When calculating device upsets at other proton energies, this approach is insensitive to an error in the number of registers assumed as the curves of Fig. 2 are nearly parallel.

Proton Flux Inside Spacecraft

The average proton flux in earth orbits is tabulated in NASA reports by Stassinopoulos.¹²⁻¹⁵ The flux varies with position in orbit, often by many orders of magnitude; see Fig. 4 of Ref. 9. As the path over the rotating earth changes, the flux integrated over an orbit period also varies. Although only the average is treated here, it is necessary, in addition, that a spacecraft be able to handle the peak upset rate.

In reaching a point within a spacecraft, protons are degraded by the material traversed. The energy loss may be computed using proton range-energy tables such as those by Janni.¹⁶

Langworthy¹⁷ has calculated the mass distribution shielding a device at a "typical" location in a light (<500 lb) spacecraft. The distribution was shown and used by Petersen.⁷ The present

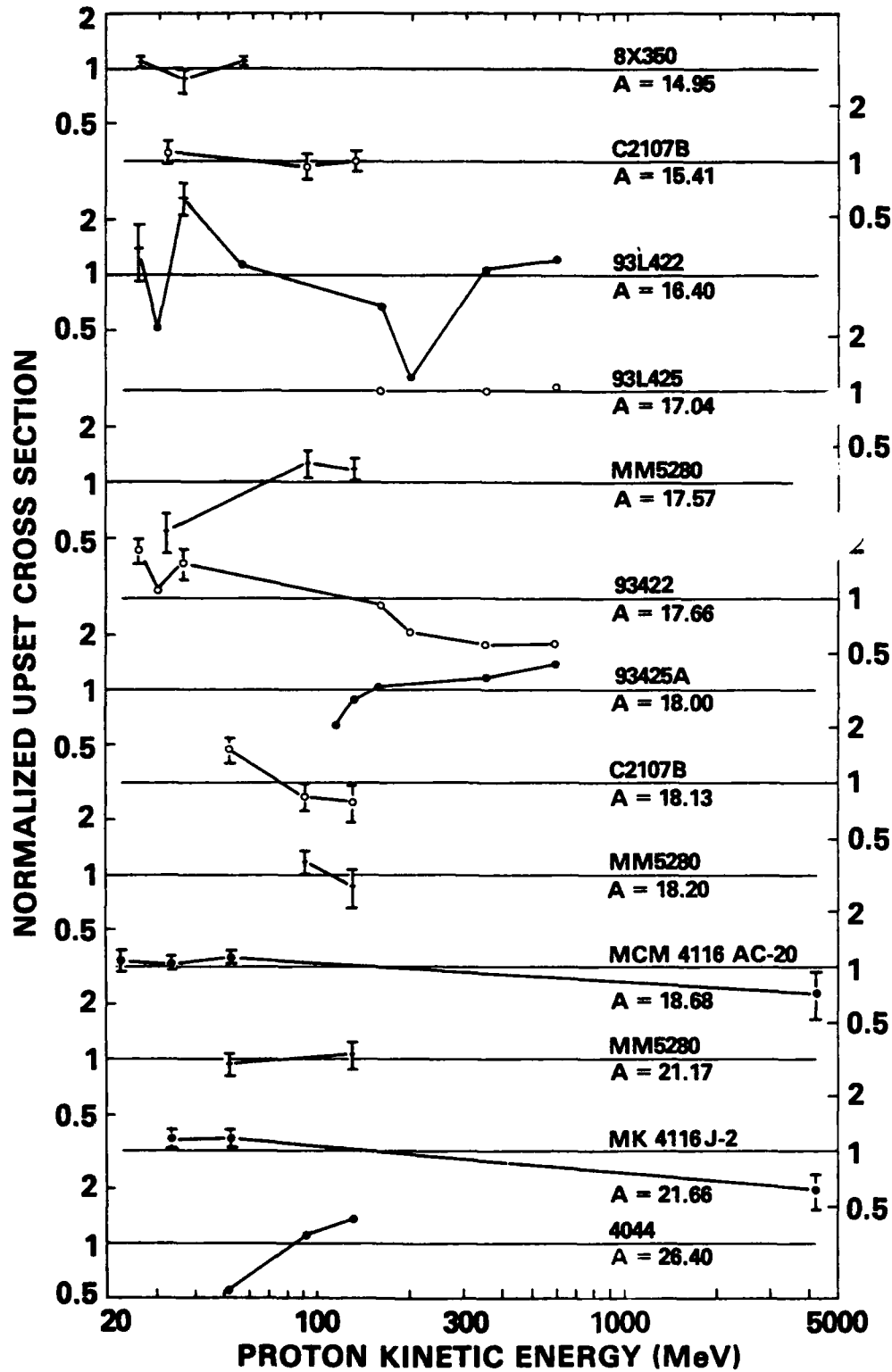


Fig. 3. Ratios of measured SEU cross sections to the values from Eq. (3) with the value of A (MeV) shown.

work employs more bins to fit Langworthy's shield, with 6% of the solid angle at each of

0.72, 0.79, 0.92, 1.12, 1.51,
2.71, 3.45, 4.73, 5.98, 7.55,
10.78, 14.53, 18.53, and 24.12 g/cm² Al,

plus 4% each at

29.97, 35.71, 42.58, and 50.85 g/cm² Al.

The resultant matrix for distribution of protons from external to internal energy bins is incorporated in the computer program in the appendix. As many protons are stopped before the device is reached, the residual proton spectrum is normally much "harder" than the initial spectrum; see Fig. 2 of Ref. 9.

The results in this report are representative values. The reader may wish to calculate the actual shielding distribution at a typical location in a given spacecraft, or the shielding around a specific device.

Upset Rates

When the internal proton flux for a given orbit is folded with the cross sections of Eq. (3) for given A, the upset rate is obtained. Let us consider a case (the case in the appendix with A = 18 MeV) in which the 80- to 100-MeV bin contains 0.232×10^6 protons/cm² per day. The cross section, Eq. (3), averages about 20.9×10^{-12} upset per proton/cm² per bit. The product is 4.85×10^{-6} upsets per bit-day for this bin only. When the products for all bins are summed, the rate is 5.73×10^{-5} , in the same units.

Stassinopoulos and Barth¹² present tables of mean proton (and electron) integral fluxes as a function of energy for 60 low-altitude circular orbit environments. Fluxes are given, for solar minimum and for solar maximum, at five altitudes and six orbit inclinations - the angle between the plane of the orbit and the plane of the earth's equator. These fluxes may be distributed to internal differential flux bins, using the "typical" shielding introduced above. The upset rate is then calculated for various values of A. Results, for six values of A from 12 to 30 MeV, are listed in Table 1 for solar minimum and in Table 2 for solar maximum.

Table 3 lists mean upset rate results for 11 other orbits. The first six cases¹³ show rate versus altitude at an inclination of 60°. The group of three¹⁴ is at fixed orbit but varying time and solar conditions. (The time specifies the geomagnetic field used in the computation.) The final two¹⁵ cases are non-circular orbits; they are proposed inclinations for the Combined Release and Radiation Effects Satellite (CRRES) orbit.

As seen from Fig. 3, upset rates are determined with limited accuracy. Both the reproducibility of devices and consistency of upset data as a function of energy leave much to be desired. "A basic uncertainty factor of 2" is stated¹² for the proton flux. In addition, the shielding pattern will vary from point to point, even in the same spacecraft. The upset rates *versus* A are thus

Table 1. Single Event Upset rates at SOLAR MINIMUM, as a function of A (MeV) and at a typical location in a light spacecraft in a circular earth orbit. Time = 1980.0. The table entries are in exponent form: $2.86-4 = 2.86 \times 10^{-4}$. The quantity B appears in Eqs. (4) and (5).

Orbit Incli- nation	Upsets per Bit-Day						B (MeV)
	A=12	A=15	A=18	A=22	A=26	A=30	
Altitude = 200 km = 108 nmi; Period = 1.475 hr							
30°	2.86-4	1.15-5	8.20-7	4.44-8	3.88-9	4.77-10	17.5
35°	7.65-4	3.02-5	2.13-6	1.14-7	9.76-9	1.18-9	12.3
40°	9.58-4	3.77-5	2.65-6	1.40-7	1.20-8	1.45-9	11.2
50°	6.16-4	2.40-5	1.68-6	8.82-8	7.50-9	8.96-10	9.3
60°	4.48-4	1.75-5	1.23-6	6.50-8	5.56-9	6.68-10	10.5
90°	3.72-4	1.46-5	1.02-6	5.41-8	4.62-9	5.55-10	10.5
Altitude = 400 km = 216 nmi; Period = 1.543 hr							
30°	1.17-2	4.75-4	3.43-5	1.88-6	1.66-7	2.06-8	22.1
35°	1.51-2	6.10-4	4.39-5	2.40-6	2.12-7	2.62-8	20.7
40°	1.38-2	5.53-4	3.97-5	2.16-6	1.90-7	2.34-8	19.0
50°	8.72-3	3.49-4	2.50-5	1.36-6	1.19-7	1.47-8	18.2
60°	7.67-3	3.09-4	2.22-5	1.21-6	1.06-7	1.31-8	19.5
90°	5.77-3	2.32-4	1.66-5	9.08-7	7.98-8	9.86-9	19.6
Altitude = 600 km = 324 nmi; Period = 1.611 hr							
30°	6.14-2	2.49-3	1.80-4	9.92-6	8.80-7	1.10-7	23.9
35°	6.20-2	2.51-3	1.81-4	9.93-6	8.79-7	1.09-7	22.3
40°	5.40-2	2.18-3	1.57-4	8.61-6	7.60-7	9.44-8	21.7
50°	3.82-2	1.54-3	1.11-4	6.09-6	5.37-7	6.67-8	21.4
60°	3.13-2	1.27-3	9.13-5	5.00-6	4.42-7	5.49-8	21.8
90°	2.74-2	1.11-3	7.99-5	4.38-6	3.88-7	4.82-8	22.3
Altitude = 800 km = 432 nmi; Period = 1.681 hr							
30°	0.172	6.96-3	5.04-4	2.78-5	2.47-6	3.08-7	24.6
35°	0.160	6.49-3	4.69-4	2.58-5	2.29-6	2.85-7	23.5
40°	0.140	5.67-3	4.09-4	2.25-5	1.99-6	2.48-7	23.0
50°	0.104	4.20-3	3.03-4	1.67-5	1.48-6	1.84-7	23.1
60°	0.0867	3.51-3	2.54-4	1.40-5	1.24-6	1.54-7	23.6
90°	0.0729	2.96-3	2.14-4	1.18-5	1.04-6	1.30-7	23.8
Altitude = 1200 km = 648 nmi; Period = 1.824 hr							
30°	0.709	2.87-2	2.08-3	1.15-4	1.02-5	1.27-6	24.1
35°	0.626	2.54-2	1.84-3	1.01-4	8.96-6	1.12-6	23.7
40°	0.538	2.18-2	1.58-3	8.67-5	7.69-6	9.57-7	23.4
50°	0.420	1.70-2	1.23-3	6.77-5	6.00-6	7.48-7	23.6
60°	0.360	1.46-2	1.06-3	5.81-5	5.15-6	6.42-7	23.9
90°	0.305	1.24-2	8.95-4	4.93-5	4.37-6	5.45-7	24.0

Table 2. Single Event Upset rates at SOLAR MAXIMUM, as a function of A (MeV) and at a typical location in a light spacecraft in a circular earth orbit. Time = 1980.0. The table entries are in exponent form: 5.24-6 = 5.24×10^{-6} . The quantity B appears in Eqs. (4) and (5).

Orbit Inclination	Upsets per Bit-Day						B (MeV)
A=12	A=15	A=18	A=22	A=26	A=30		
Altitude = 200 km = 108 nmi; Period = 1.475 hr							
30°	5.24-6	2.16-7	1.58-8	8.82-10	7.92-11	9.98-12	32.1
35°	6.49-5	2.59-6	1.84-7	9.93-9	8.62-10	1.05-10	15.4
40°	1.94-4	7.67-6	5.42-7	2.90-8	2.49-9	3.02-10	12.9
50°	1.14-4	4.49-6	3.17-7	1.69-8	1.45-9	1.75-10	12.4
60°	8.57-5	3.40-6	2.40-7	1.29-8	1.11-9	1.35-10	13.5
90°	6.46-5	2.55-6	1.80-7	9.62-9	8.28-10	1.00-10	12.7
Altitude = 400 km = 216 nmi; Period = 1.543 hr							
30°	5.65-3	2.30-4	1.68-5	9.29-7	8.29-8	1.04-8	27.5
35°	7.78-3	3.16-4	2.28-5	1.26-6	1.11-7	1.39-8	23.5
40°	7.30-3	2.95-4	2.13-5	1.17-6	1.03-7	1.28-8	22.0
50°	4.63-3	1.87-4	1.35-5	7.38-7	6.51-8	8.08-9	21.4
60°	3.98-3	1.61-4	1.16-5	6.36-7	5.62-8	6.98-9	22.0
90°	2.94-3	1.19-4	8.58-6	4.71-7	4.16-8	5.17-9	22.3
Altitude = 600 km = 324 nmi; Period = 1.611 hr							
30°	3.83-2	1.56-3	1.13-4	6.25-6	5.56-7	6.95-8	25.6
35°	3.90-2	1.58-3	1.15-4	6.30-6	5.59-7	6.96-8	23.7
40°	3.52-2	1.42-3	1.03-4	5.64-6	4.99-7	6.21-8	22.7
50°	2.43-2	9.84-4	7.11-5	3.90-6	3.45-7	4.29-8	22.6
60°	1.96-2	7.93-4	5.73-5	3.15-6	2.79-7	3.47-8	23.1
90°	1.74-2	7.05-4	5.10-5	2.80-6	2.48-7	3.09-8	23.4
Altitude = 800 km = 432 nmi; Period = 1.681 hr							
30°	0.122	4.95-3	3.59-4	1.98-5	1.76-6	2.20-7	25.4
35°	0.113	4.60-3	3.33-4	1.84-5	1.63-6	2.03-7	24.5
40°	0.0986	4.00-3	2.89-4	1.59-5	1.41-6	1.76-7	23.8
50°	0.0728	2.95-3	2.13-4	1.17-5	1.04-6	1.30-7	23.8
60°	0.0605	2.45-3	1.78-4	9.79-6	8.69-7	1.08-7	24.5
90°	0.0508	2.06-3	1.49-4	8.23-6	7.31-7	9.13-8	24.8
Altitude = 1200 km = 648 nmi; Period = 1.824 hr							
30°	0.550	2.23-2	1.62-3	8.90-5	7.90-6	9.87-7	24.5
35°	0.487	1.98-2	1.43-3	7.87-5	6.98-6	8.71-7	24.1
40°	0.422	1.71-2	1.24-3	6.80-5	6.03-6	7.52-7	23.8
50°	0.326	1.32-2	9.56-4	5.26-5	4.67-6	5.82-7	24.0
60°	0.278	1.13-2	8.17-4	4.50-5	3.99-6	4.98-7	24.3
90°	0.236	9.57-3	6.93-4	3.82-5	3.39-6	4.23-7	24.4

Table 3. Single Event Upset rates as a function of A (MeV) and at a typical location in a light spacecraft in an earth orbit. The table entries are in exponent form: $4.20-2 = 4.20 \times 10^{-2}$. B is used in Eq. (5).

Orbit Incli- nation	Upsets per Bit-Day						B (MeV)
	A=12	A=15	A=18	A=22	A=26	A=30	
Solar Maximum; Time = 1989.5							
Altitude = 1667 km = 900 nmi; Period = 1.995 hr							
60°	1.04	4.20-2	3.03-3	1.67-4	1.47-5	1.83-6	22.6
Altitude = 2593 km = 1400 nmi; Period = 2.349 hr							
60°	2.33	9.34-2	6.69-3	3.64-4	3.20-5	3.95-6	19.1
Altitude = 3889 km = 2100 nmi; Period = 2.876 hr							
60°	1.16	4.53-2	3.18-3	1.69-4	1.45-5	1.76-6	11.5
Altitude = 5186 km = 2800 nmi; Period = 3.438 hr							
60°	0.318	1.20-2	8.19-4	4.20-5	3.50-6	4.14-7	5.0
Altitude = 6389 km = 3450 nmi; Period = 3.988 hr							
60°	8.82-2	3.20-3	2.10-4	1.03-5	8.28-7	9.45-8	(0.0)
Altitude = 10,371 km = 5600 nmi; Period = 5.992 hr							
60°	7.87-4	2.42-5	1.36-6	5.39-8	3.53-9	3.33-10	
Altitude = 1111 km = 600 nmi; Period = 1.792 hr							
Solar Max; Time = 1981.8							
63°	0.194	7.86-3	5.69-4	3.14-5	2.78-6	3.48-7	24.4
Solar Min; Time = 1985.8							
63°	0.270	1.09-2	7.91-4	4.35-5	3.86-6	4.81-7	23.9
Solar Max; Time = 1989.0							
63°	0.224	9.11-3	6.59-4	3.63-5	3.22-6	4.02-7	24.2
CRRES: 360 to 36000 km; 194 to 19438 nmi; Period = 10.639 hr							
Solar Minimum; Time = 1985.0							
11°	0.274	1.09-2	7.77-4	4.20-5	3.67-6	4.51-7	16.5
21°	0.147	5.85-3	4.16-4	2.25-5	1.96-6	2.41-7	16.2

uncertain by more than a factor of 2. The SEU rates for devices are even less well known. Relative values are more accurate. The results are sufficient for many purposes, but the limitations must be kept in mind.

The upset rates of Table 1 or 2 are values at points in the three-dimensional space of inclination, altitude, and apparent threshold. Most devices and orbits will not have the values in the table. In order to determine the upset rate in the general case, one must interpolate in all three variables. Interpolation in A will be found to be simple and accurate. Interpolation in orbit, particularly altitude, will be less accurate.

Upset Rate versus A

A plot of upset rate, U, versus A from 12 to 30 MeV, requires

6- or 7-cycle graph paper and cannot be read accurately. The primary cause is the $(24/A)^{14}$ factor in Eq. (3). Without it, the variation would be about a factor of 1.5 (see the printout in the appendix) and a graph could be read much more accurately.

A function which is sufficiently constant would eliminate the need of a U versus A graph. This is a necessary procedure for untabulated orbits - considered below - where U is mapped only for A = 18 MeV. For the orbit "constant", we adopt

$$C = A^{14} U (A + B). \quad (4)$$

With U(18) as the input datum, this approximation formula yields

$$U(A)/U(18) = (18/A)^{14} (18 + B)/(A + B). \quad (5)$$

The value of B, chosen to minimize the variation of C from C(18) for the orbit considered, is given in the last column of Tables 1-3. The formula is surprisingly accurate in the region where interpolation of U versus orbit coordinates is most accurate, and is quite satisfactory except at the highest altitude of Table 3. [The error in Eq. (5), for integer A of 12 to 30, is <0.18% at 600 to 2593 km, <0.24% for CRRES, <0.43% at 400 km, and <2.0% at 200 to 5186 km.] The dependence of U upon B is small, thus the interpolation of B between orbits can be done quite crudely; note the big change in B between 30° and 35° orbits at 600 km (Table 1 or 2) and the small difference in the slope of U.

SEU Rate Plots

The calculated upset rates in 60° orbits are shown for solar max in Fig. 4, as a function of altitude and A. Data below 800 nmi are for year 1980; data above are for 1989.5. The upset rate is small at both low and high altitude, reaching a maximum near 1400 nmi (2593 km). Also shown are the rates at 1400 nmi for the devices of Figs. 1 and 3. For A = 18 MeV and this altitude, the upset rate is 0.0067 SEU per bit-day. Of these upsets, only 4.4% are caused by protons having internal energy of 50 MeV or less.

The proportion of upsets produced by various parts of the proton spectrum will vary with A and orbit. Let us assume 80 MeV as the boundary between short-range and penetrating parts of the external proton flux. For the cases of Fig. 4 at A = 18, the external protons with less than 80 MeV energy produce 6 to 10 percent of the upsets at 108 to 1400 nmi - and most of these are due to the 60-80 MeV bin. It is evident that moderate shielding changes will have modest effect in this environment.

For the higher altitude cases, this portion increases to 15, 24, 36, and finally 82 percent at 5600 nmi. Additional shielding will be effective against proton-induced SEUs at high altitude, but shielding is not the route to complete elimination of SEUs. The range of 80 MeV protons is 6.68 g/cm² of aluminum.¹⁴ If the spacecraft has an area of 5 square meters, additional shielding of 6 g/cm² to stop all protons of <80 MeV would add 660 lb to the

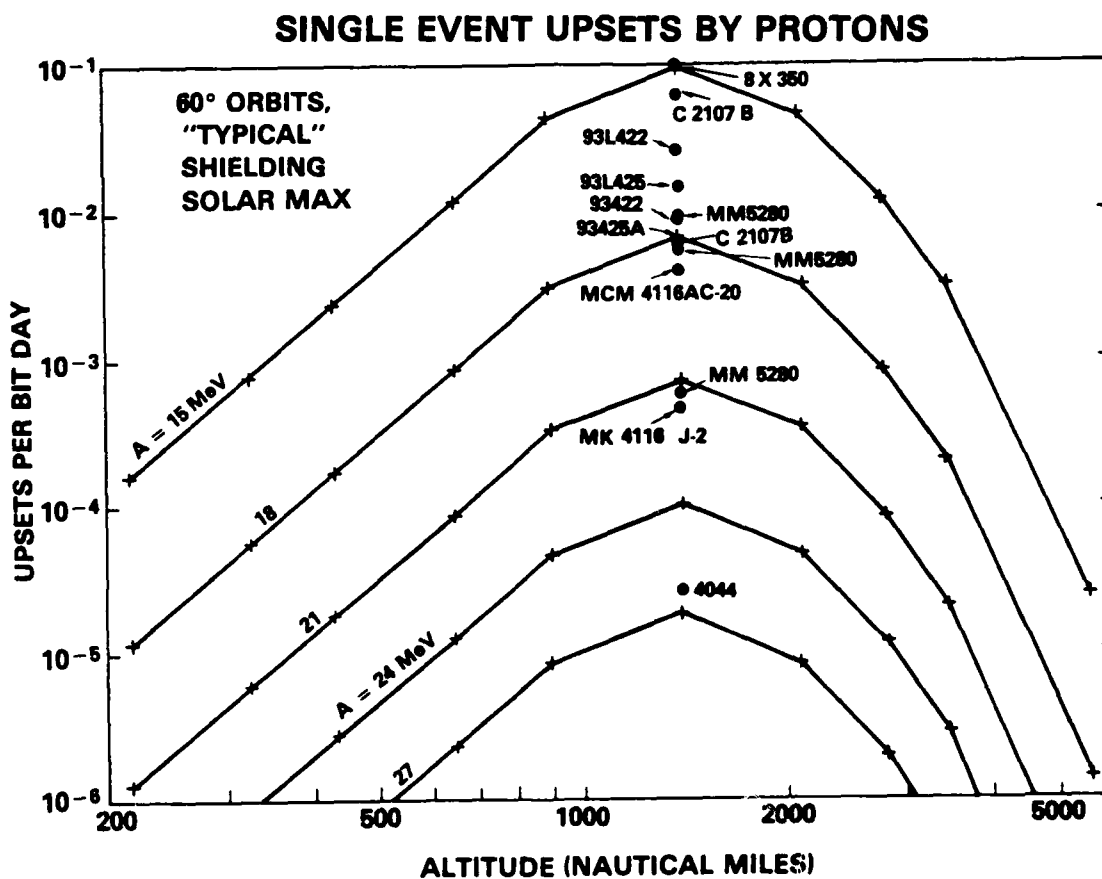


Fig. 4 Upset rates versus altitude and apparent threshold. The environment is that for typical shielding and solar maximum, in circular orbits at 60°. The rates for devices at 1400 nmi use the values of A from the data of Fig. (1) and shown in Fig. (3).

spacecraft mass. Protons of higher energy would still produce upsets.

SEU rates for $A = 18$ MeV are shown in various ways for the orbits of Tables 1 and 2. These orbits are all below the peak of the proton belts. Figs. 5 and 6, therefore, show that the upset rate increases with altitude at all inclinations. The lines are only slightly curved on these log-log plots, except for the 200 km points at low inclination.

Figure 7 shows that the variation of upset rate with orbit angle is rather small. At the lower altitudes, there is a peak at intermediate inclination; at the higher altitudes, the rate increases as the orbit becomes more equatorial. In all cases, the upset rate is higher at solar minimum, markedly so at 200 km.

It must be emphasized that single event upsets will also be produced by cosmic rays. The intense ionization along the path of a highly-ionized atom allows upset without a nuclear reaction. For many orbits, cosmic rays will be the major source of upsets. The CRRES orbit, with altitude limits of 360 and 36,000 km, will permit investigations over a wide range of space environments. Single event upsets by protons should occur primarily when the satellite traverses the heart of the radiation belt. For protons only, the peak SEU rate for the 21° CRRES orbit is expected to be about 60 times the average rate.

The Solar Max Mission satellite had an orbit at 278 nmi and 29° . Interpolating in Table 2, 13.5 upsets are calculated for a 1024-bit 93422 device in 6 months. Stewart¹⁰ reports that 10 upsets occurred under these conditions, in remarkably good agreement with our prediction. These upsets are attributed to protons because they are seen only when traversing the proton belts at the South Atlantic Anomaly.

Interpolation in Circular Orbits

Figures 5-7, which cover a range of 5.6 cycles in U, can be improved upon for use in interpolation. What is actually graphed is $\log U$, and it is seen to be rather linear with $\log H$, where H is the altitude in km. As many of the points of Fig. 7 are on nearly-parallel lines, adding a term similar to $\log H$ will yield a function more suited for interpolation.

We want to reduce the range of the function, but not make the lines overlap, preferably not even cross. A 1.1-cycle graph is adequate when the function

$$W_{min} = \log U + 0.75 \sin(\text{Inclination}) - 2.77 \log [(H-55)/745] \quad (6)$$

is plotted for solar minimum in Fig. 8. For solar maximum, we define and plot the related function

$$W_{max} = W_{min} + 102/H. \quad (7)$$

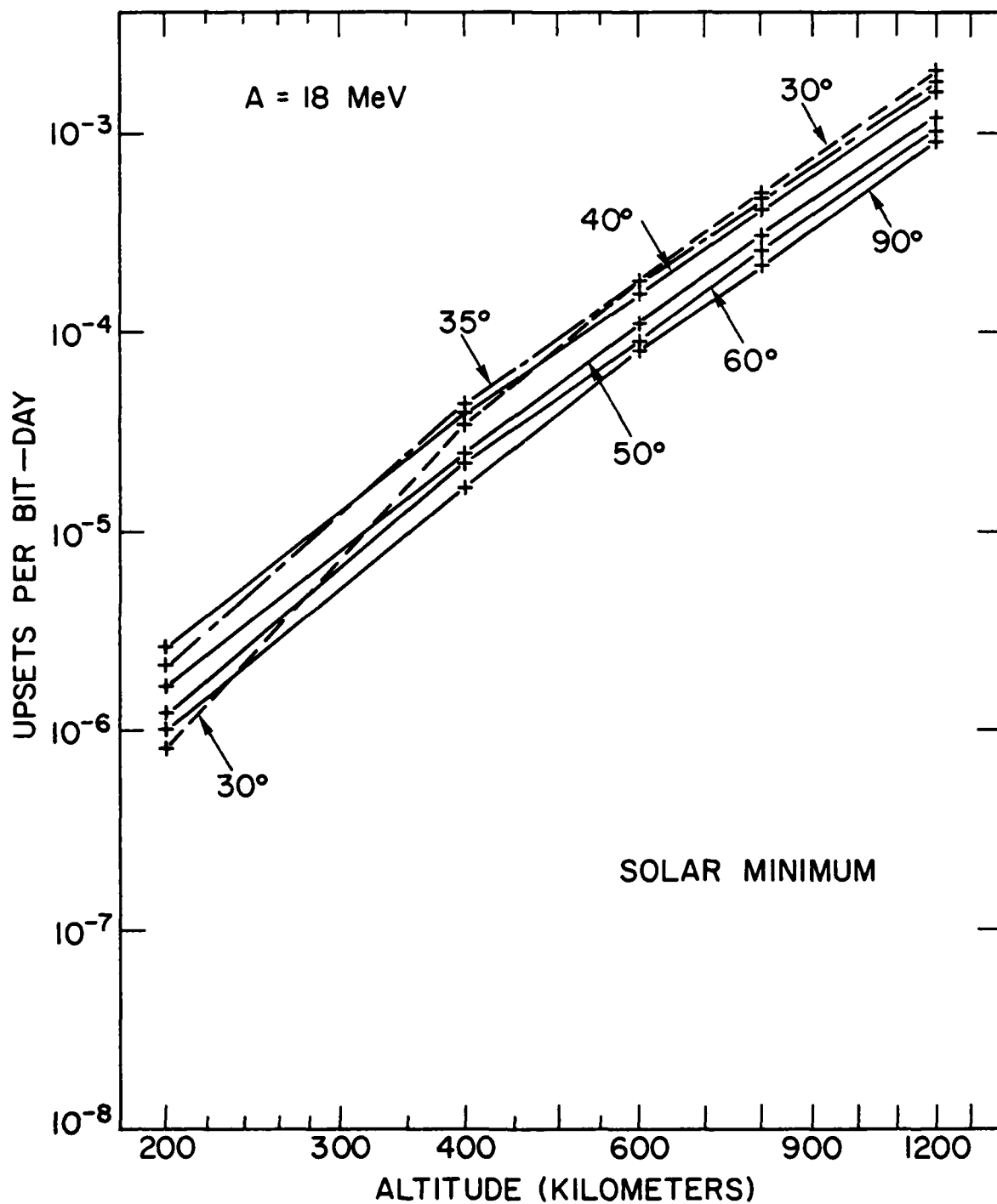


Fig. 5 Predicted solar minimum SEU rates versus altitude, for shielded devices. The points are the thirty A = 18 MeV values from Table 1.

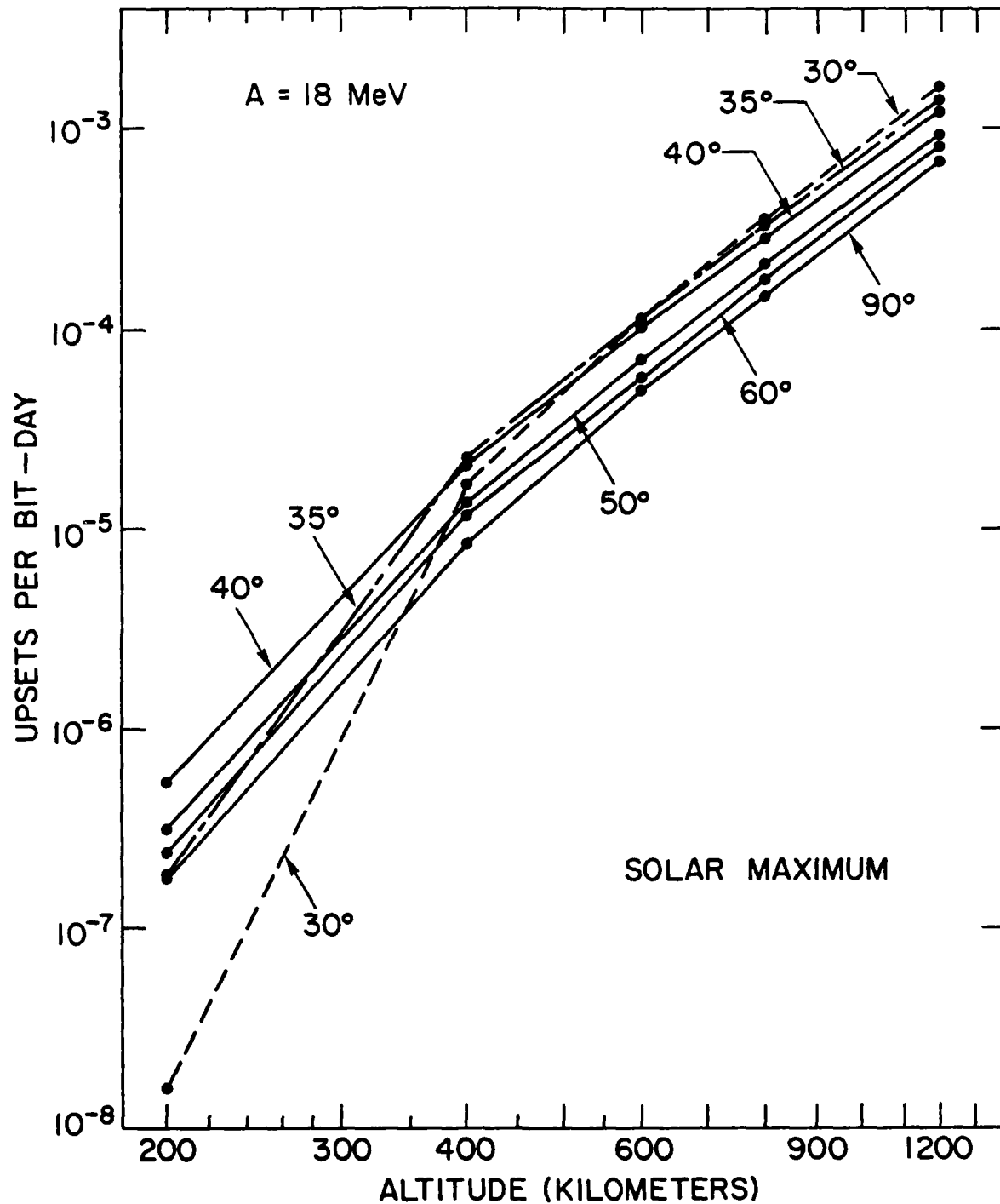


Fig. 6 Predicted solar maximum SEU rates versus altitude, for shielded devices. The points are the thirty A = 18 MeV values from Table 2.

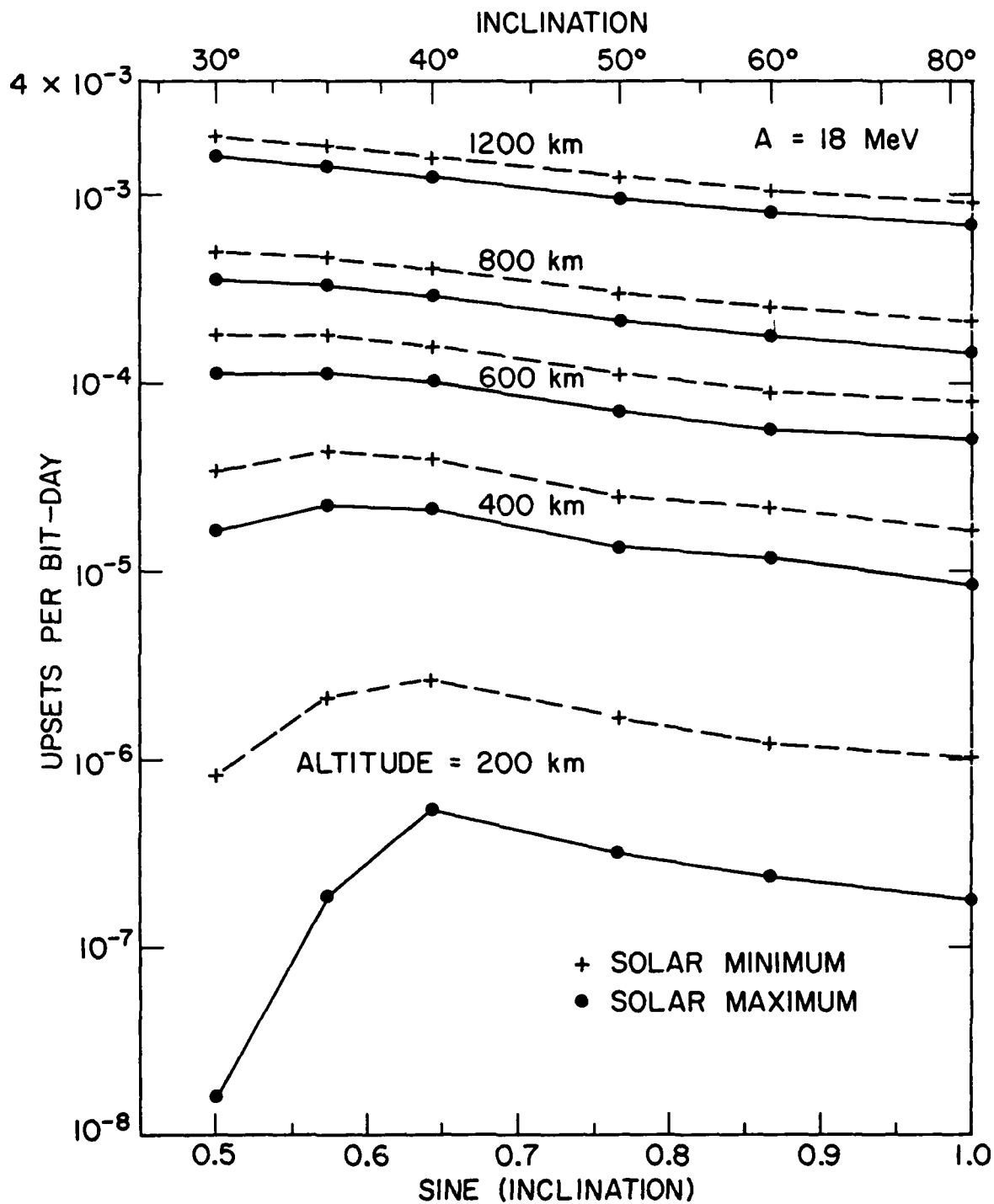


Fig. 7 Predicted SEU rates versus orbit angle, for shielded devices. The sixty A = 18 MeV values from Tables 1 and 2 are used.

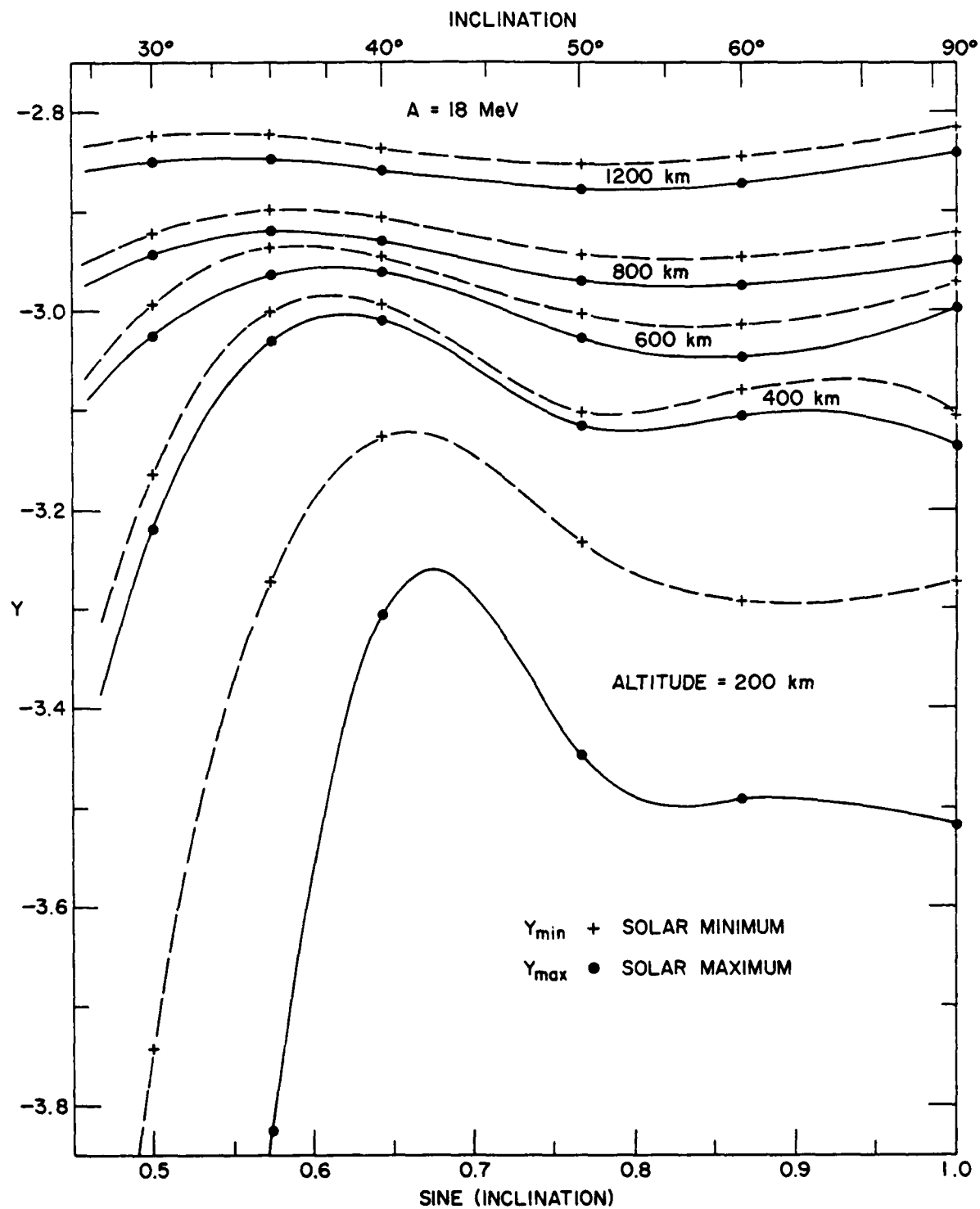


Fig. 8 Graph for SEU rate interpolation; logarithmic functions versus orbit angle, for shielded devices, $A = 18$ MeV.

Except at 200 km, the two sets of data track very well with a difference of about 0.025. The figure suggests that the accuracy of interpolation in altitude (not to be confused with accuracy of the input data) is rather good above 400 km, and rather poor at lesser altitude. [The curves represent a cubic spline fit to the quantity $-1/(1.6+W)$ at the 6 angles, then evaluated at 15 others. Some of the 200 km, solar max, points are altered up to .007 as a compromise with other types of fits.]

For values of A other than 18 MeV, one first finds $\log U(18)$ from Fig. 8 and Eq. (6) or (7), then uses Eq. (5).

SEU Contour Maps

The upset rate may also be presented for circular orbits as a contour map in the sine(inclination), altitude plane. This is done, again using the A = 18 MeV upset rates (Tables 1 and 2) calculated from the orbital flux tables of Stassinopoulos and Barth¹². The Solar Minimum case is Fig. 9, and Solar Maximum is Fig. 10. These maps seem to illustrate the relative SEU rates expected in this altitude range better than Figs. 5-7, and allow quite accurate interpolation more easily than with Fig. 8.

The contours above 400 km are readily interpolated from the computed points, but those at lower altitude are often uncertain, notably for solar maximum and at small orbit inclination. [The high-altitude W's at each of 21 angles (spline fit, above) define the cubic in $\log (H/800)$ used for W above 400 km. A term in the square of $\log (H/400)$ is added below 400 km and fitted at 200 km.]

Figures 9 and 10 permit a simple, and reasonably accurate, way of obtaining the upset rate at any value of the parameter A. After reading an upset rate for A = 18 MeV from the appropriate map, employ Eq. (5) to obtain the rate at the desired value of A. It is necessary to find B from Table 1 or 2, but a rough interpolation is adequate.

The CRRES satellite is to be in a highly-elliptical, rather equatorial orbit, with proton environment about equal to that of a circular orbit at 1000 km altitude. Let us compare it with a 1980, 60°, solar minimum orbit using Fig. 8 or 9. The predicted upset rate for CRRES at A = 18 MeV is equal to that at about 920 km for the 21° orbit and 1100 km for the 11° case.

Summary

This report presents a method of predicting proton-induced SEU rates in spacecraft and elsewhere. The method, introduced in Ref. 1, is then used to tabulate and graph results for 71 orbits. Methods of interpolating SEU rates between orbits are presented.

Experimental upset data are obtained at one or more energies, usually with a cyclotron. These data determine the parameter A of Eq. (3) and, therefore, the cross section at all energies. When the proton environment (including the effect of shielding)

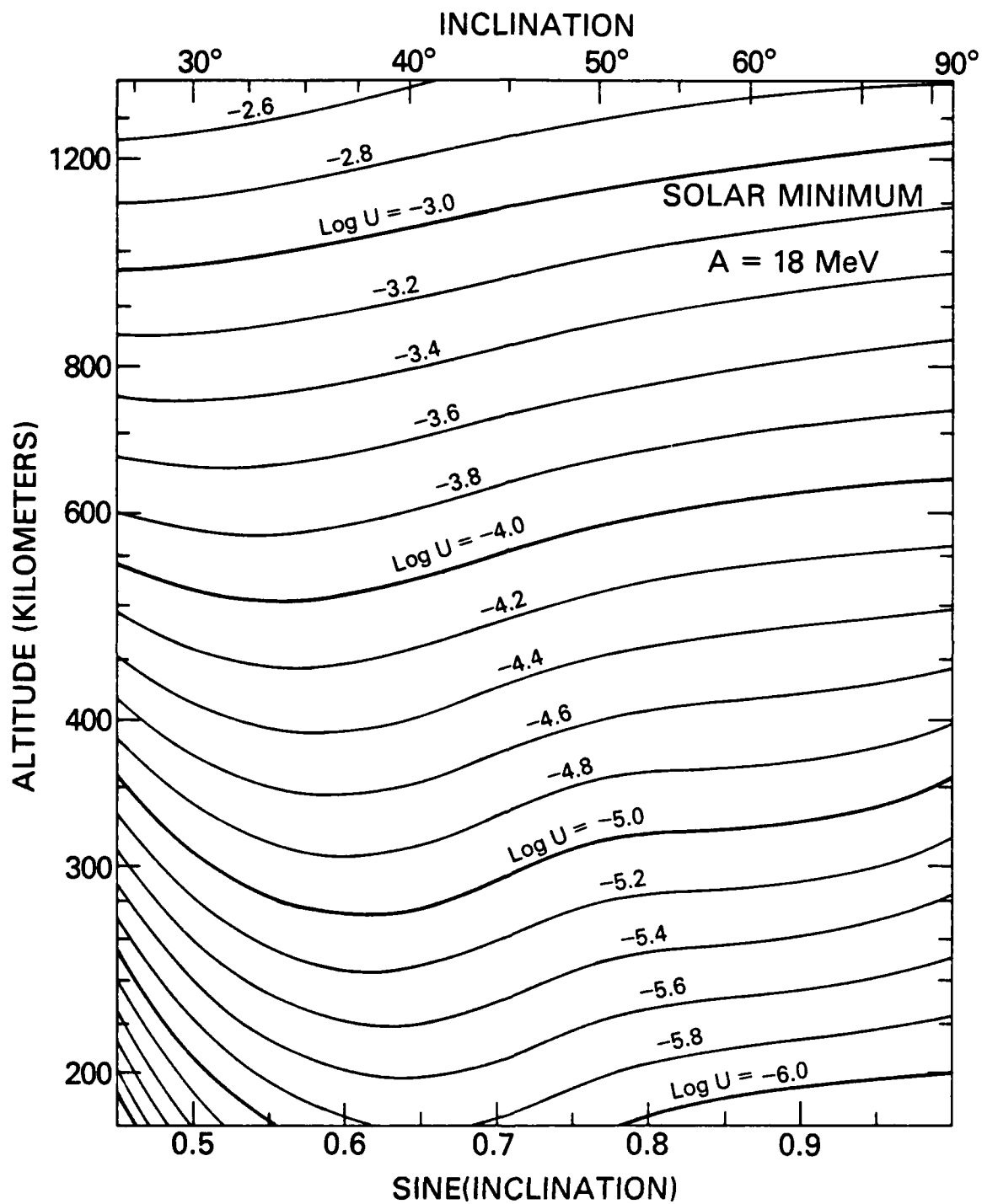


Fig. 9 SEU contour map for circular orbits at solar minimum and A = 18 MeV. The rate, U, is in units of upsets per bit-day.

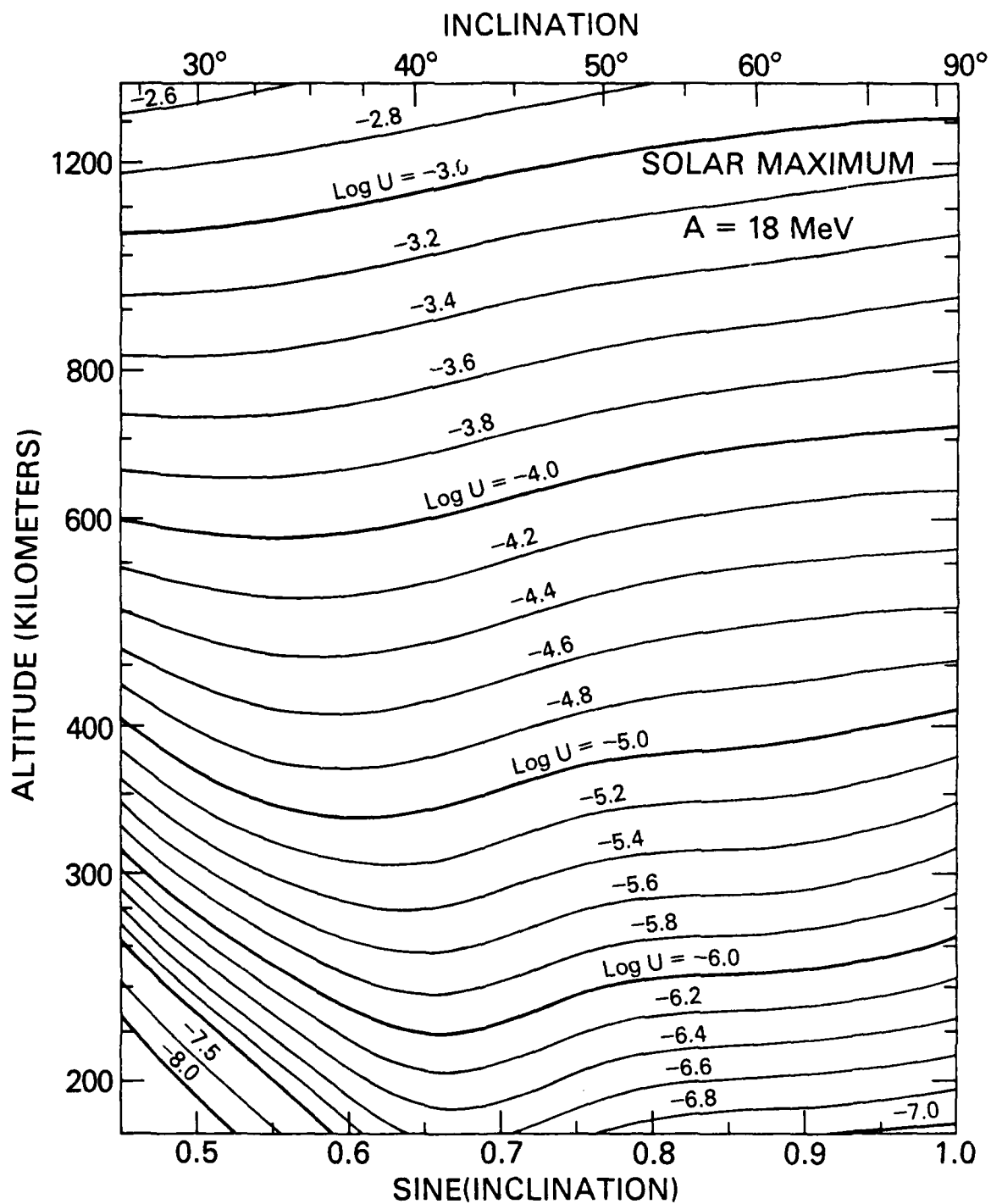


Fig. 10 SEU contour map for circular orbits at solar maximum and A = 18 MeV. The rate, U, is in units of upsets per bit-day.

is specified, the single event upset rate may be computed for a given device -- or tabulated versus the figure of merit, A, as is done here.

The computer program employed, which incorporates the effect of typical shielding in light spacecraft, is listed together with a sample of the input and output data.

Acknowledgments

The work is a continuation, in a little different direction, of studies done by Ed Petersen.⁹⁻¹⁰ This report follows Ref. 1, of which he is co-author. Although much material is new, this report necessarily echos much of the earlier text. Clearly, the author is greatly indebted to Dr. Petersen; his ideas and words cannot be expunged from the present report.

Thanks are also due to Jim Ritter and Jim Langworthy for many useful discussions and to C.H. Tsao for pointing out Ref. 11.

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Appendix: Computer Program

The early calculations were done without a "computer", but an HP-97 "programmable calculator" was employed. Once the method and equations were developed, an IBM Personal Computer was used to speed calculations on all orbits for which proton spectra were on hand. The IBM Advanced Basic program listed on pages 26 and 27 produced the data of Tables 1-3. The symbols do not agree with those in the main text of this report; parameter A appears as K in the program. Figures in curly brackets, e.g. {500}, are program line numbers.

The proton spectra of Refs. 12-15 were listed on work sheets (top, page 28), together with orbit specifications. These specs are input {400, 410} so that the output (bottom, page 28) may include orbit identification; height in nautical miles {470} and orbit period {500} are incidental calculations. A spectrum is input {420-450} as integral fluxes, F, at 16 minimum energies, from 25 to 500 MeV. A 17th value is generated {560}, and the differential external flux, X, is calculated for 17 energy bins.

The external flux is converted to internal (central) flux, C, in 22 bins {690-760} using a 17x22 matrix {90-270}. The internal bins {320-330} have the same energy spans as the external bins, but bins are added for four groups of slow protons and for the protons stopped before reaching the interior. [A 25-MeV proton, after passing through the minimum shield, has an energy of 8.4 MeV. The input data, therefore, are inadequate if protons under this energy can produce upsets.]

For given apparent threshold $A=K$ {810-830}, the upset rate is calculated {880 up} by summing over bins {1010}, using the cross sections at three points for each bin. If the expected average energy differs {370, 380} from the midbin energy, a correction is made {1000}.

For computation of only those upsets due to protons under 80 MeV, {621} $X(J) = 0$ and {622} IF $J > 6$ GOTO 640 were added.

The variation of U (upsets per bit-day) with the threshold is primarily due to the 14th-power factor in Eq. (3). The result without this factor, Z {1040}, is slowly varying and is printed with U and log U.

11-03-1983

```

10 REM External to Internal Proton Spectrum; Upsets vs. K
20 DEFINT I-N: DEFENS A-H, O-Z
30 DIM M(21,16), F(16), X(16), C(21) 'Integral flux, Xternal, Center
40 FOR I = 0 TO 21
50   FOR J = 0 TO 16
60     IF I>(J+5), THEN M(I,J) = 0 ELSE READ M(I,J)
70   NEXT J
80 NEXT I
90 DATA 829,755,700,700,700, 612,525,418,356,277, 177, 78, 9,0,0, 0,0
100 DATA 138,59, 40, 0, 0, 21, 13, 7, 5, 6, 3, 2, 1,0,0, 0,0
110 DATA 33, 67, 27, 2, 0, 19, 7, 3, 3, 3, 1, 1,0,0,0, 0,0
120 DATA 0, 50, 15, 14, 0, 10, 4, 2, 1, 2, 1,0,0,0,0, 0,0
130 DATA 0, 69, 90, 36, 0, 16, 16, 7, 5, 5, 2, 2, 1,0,0, 0,0
140 DATA 0, 0,119, 72, 34, 15, 16, 14, 5, 5, 2, 1, 1,0,0, 0,0
150 DATA 0, 9,148, 64, 16, 22, 14, 6, 7, 3, 2, 1,0,0, 0,0
160 DATA 0, 28,154, 36, 28, 15, 6, 5, 5, 3, 1,0,0, 0,0
170 DATA 0, 48, 109, 21, 25, 6, 4, 6, 2, 1,0,0, 0,0
180 DATA 0, 107, 32, 20, 17, 5, 7, 3, 2,0,0, 0,0
190 DATA 39,149, 54, 21, 22, 12, 9, 2, 0, 0, 0,0
200 DATA 167,226,107, 45, 31, 18, 11, 0, 0, 0,0
210 DATA 195,240, 90, 44, 23, 16, 0, 0, 0,0
220 DATA 222,210, 60, 31, 20, 0, 0, 0,0
230 DATA 314, 215, 71, 39, 16, 0, 0,0
240 DATA 431,288,105, 60, 1, 0,0
250 DATA 466,297,110, 50, 0, 0
260 DATA 493,300,112, 22, 0
270 DATA 514,306, 78, 0, 531,237,6, 663,195, 799
280 DIM L(22), D(21) 'LowerLimit, (av MeV of protons) - midbin
290 FOR I = 0 TO 22
300   READ L(I)
310 NEXT I
320 DATA 0,0,14,18,20, 25,30,35,40,45
330 DATA 50,60,80,100,120, 150,200,250,300,350, 400,500,926
340 FOR I = 0 TO 21
350   READ D(I)
360 NEXT I
370 DATA 0,2,0,.04,.04, -.04,-.06,-.08,-.09,-.05
380 DATA -.14,-.3,-.5,-.4,-.8, -2.4,-2.2,-2.1,-2,-2, -8,-128
390 PRINT "Key in orbit and 16 integral fluxes"
400 INPUT "Inclination, altitude in km"; BB, KM
410 INPUT "Solar max (9) or min (0), year"; MM, YY
420 PRINT "": INPUT "5 fluxes, 25+ to 45+ MeV"; F(0),F(1),F(2),F(3),F(4)
430 PRINT "": INPUT "4 more, 50+ to 100+ MeV"; F(5), F(6), F(7), F(8)
440 PRINT "": INPUT "5 more, 150+ to 350+ MeV"; F(10),F(11),F(12),F(13),F(14)
450 PRINT "": INPUT "Last 2 fluxes, 400+ and 500+ MeV"; F(15), F(16)
460 LPRINT "Inclination ="; BB; "degrees"
470 NM = KM/1.852
480 LPRINT "Altitude ="; KM; "km ="; NM; "nmi"
490 IF MM = 0, THEN SS$ = "Solar min, Time =" ELSE SS$ = "Solar Max, Time ="
500 VV = (6378.137 + KM)/5076.85: TT = VV ^ 1.5
510 LPRINT SS$:
520 LPRINT USING "#####.#": YY;
530 LPRINT SPC(11); "Period =";
540 LPRINT USING "###.###": TT;
550 LPRINT " hours" 'Orbit params take 3 lines
560 F(9) = (F(8)^.6) * (F(10)^.4): X(16) = F(16)

```

```

570 WIDTH "LPT1:", 60
580 FOR J = 0 TO 16
590   LPRINT USING "#####.##### "; F(J);
600   NEXT J
610 LPRINT " end. integral Flux list"
620 FOR J = 0 TO 15
630   X(J) = F(J) - F(J+1)
640   LPRINT USING "#####.##### "; X(J);
645   IF X(J)<0 GOTO 850 'Input error
650   NEXT J
660 LPRINT USING "#####.##### "; X(16);
670 LPRINT " end. Xternal flux bin list": LPRINT CHR$(10);
680 S = 0 'sum of C
690 FOR I = 0 TO 21
700   C(I) = 0
710   FOR J = 0 TO 16
720     C(I) = M(I,J)*X(J) + C(I)
730   NEXT J
740   C(I) = C(I) * .001: S = C(I) + S
750   LPRINT USING "#####.##### "; C(I);
760   NEXT I
770 LPRINT USING "#####.##### "; S;
780 LPRINT "= sum, Central bins"
790 WIDTH "LPT1:", 80
800 LPRINT " A=K U*(K/24)^14      U      Log U";SPC(20);"Upsets/Bit-Day"
810 FOR N = 12 TO 23
820   K = N: GOSUB 880
830   K = N + 12: GOSUB 880
840   NEXT N
850 BEEP: PRINT " "
860 LPRINT CHR$(10) CHR$(10) CHR$(7)
870 GOTO 390
880   Q = 0: W = SQR(18/K)
890   FOR I = 1 TO 21
900     IF K >= L(I+1) GOTO 1020
910     IF K > L(I) GOTO 1090
920     R = D(I)/2: EA = L(I): H = 1
930     EB = (L(I+1) + EA)/2
940     EQ = (EB - EA)*.7745967
950     E = EB: GOSUB 1110
960     T = 1.6*G
970     E = EB + EQ: GOSUB 1110
980     GC = G: T = G + T
990     E = EB - EQ: GOSUB 1110
1000    T = (GC - G)*R/EQ + (G + T)/3.6
1010    Q = T*H*C(I) + Q
1020    NEXT I
1030    LPRINT K;
1040    Z = Q * .000001: U = (24/K)^14 * Z
1050    LPRINT USING "###.####^#### "; Z; U;
1060    V = .4342945 * LOG(U)
1070    LPRINT USING "###.###      "; V;
1080    RETURN
1090    R = 0: EA = K: H = (L(I+1)-K)/(L(I+1)-L(I))
1100    GOTO 930 'K within bin
1110 Y = (E - K)*W 'Energy-dependent func subr
1120 P = -.18 * SQR(Y)
1130 G = (1 - EXP(P))^4
1140 RETURN
1150 END 'EXTINTP.UPK

```

Table 155

Inclination: 60°

Perigee: 600 km
Apogee:

Solar (MAX) or (min)

Year: 1980.0

INTEGRAL FLUX, E (MeV) to infinity

in units of 10^6 protons/cm² per day

25	30	35	40	45
4.013	3.794	3.605	3.429	3.264
50	60	80	100	120
3.110	2.809	2.305	1.904	
150	200	250	300	350
1.120	.6780	.4001	.2401	.1449
400	500			
.08979	.03277	✓ Period: <u>1.611</u> hrs		

Table 157

Inclination: 90°

Perigee: 600 km
Apogee:

Solar (MAX) or (min)

25	30	35	40	45
3.515	3.327	3.166	3.016	2.875
50	60	80	100	120
2.743	2.481	2.042	1.691	
150	200	250	300	
1.000				

Inclination = 60 degrees

Altitude = 600 km = 324 nmi

Solar Max. Time = 1980.0

Period = 1.611 hours

4.01300	3.79400	3.60500	3.42900	3.26400
3.11000	2.80900	2.30500	1.90400	1.53988
1.12000	0.67400	0.40010	0.24010	0.14490
0.08979	0.03277	end, integral flux list		
0.21900	0.18900	0.17600	0.16500	0.15400
0.30100	0.50400	0.40100	0.36412	0.41938
0.44600	0.27390	0.16000	0.09520	0.05711
0.05502	0.03277	end, xternal flux bin list		

1.63486	0.07048	0.03849	0.02188	0.05600
0.06150	0.06455	0.06679	0.06806	0.06891
0.13351	0.15317	0.23186	0.20746	0.25494
0.29368	0.13848	0.11505	0.07070	0.04356
0.04287	0.00518	4.01300 = sum, Central bins		

A = U * (K/24) * 14

U Log U

Upsets/Bit-Day

12	1.1945E-06	1.9571E-02	-1.708	24	8.9130E-07	8.9130E-07	-8.050
13	1.1610E-06	8.3029E-07	-2.207	25	8.7208E-07	4.9278E-07	-8.707
14	1.1296E-06	1.1384E-07	-2.870	26	8.5474E-07	2.7372E-07	-8.355
15	1.1000E-06	7.9265E-04	-3.101	27	8.3742E-07	1.6199E-07	-8.783
16	1.0721E-06	7.1297E-04	-3.504	28	8.2070E-07	9.4826E-08	-7.021
17	1.0456E-06	1.5063E-04	-3.884	29	8.0453E-07	5.6876E-08	-7.145
18	1.0205E-06	5.7271E-05	-4.242	30	7.8868E-07	1.4695E-08	-7.460
19	9.9649E-07	2.6275E-05	-4.581	31	7.7373E-07	2.1502E-08	-7.686
20	9.7362E-07	1.2500E-05	-4.903	32	7.5904E-07	1.3525E-08	-7.569
21	9.5174E-07	6.1717E-06	-5.210	33	7.4479E-07	8.6257E-09	-8.064
22	9.3077E-07	3.1469E-06	-5.502	34	7.3095E-07	5.5737E-09	-8.254
23	9.1065E-07	1.6524E-06	-5.782	35	7.1752E-07	3.6462E-09	-8.438

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